

			02.11.2	
RefMat No	38		Category 1 Critical Dimensions	
	COMAR		Category 2 Lateral (X-Y-axis, 1-dim)	
	and the second s		Category 3 Single Step	
			Category 4	
T			Category 5	
			,,	
combina	ation of step height and pitch			
	Included in Coldmasse: Green 1 -> YES Blue 0 -> NO Included in Category 3 ype of RefMat: RM ame of RM: NanoLattice (TM) (NLSM) 100 nm pich standard scripton Surface: Topography Standards: (STS), gratings with near perfect periodicity combination of step height and pich. Link http://www.vlsistandards.com/products/dimensional/ststandards.asp?sid=47 Link http://www.vlsistandards.com/products/dimensional/ststandards.asp?sid=47 Catiloration of AFM Gatiloration of Step height MeanValue 18 MeanValue 180 Catiloration of AFM Catiloration of Step height MeanValue 180 MeanValue 180 Catiloration of AFM Catiloration of SteM Catiloration of SteM Catiloration of SteM Catiloration of MeanValue Devicer No 3 Web address http://www.vlsistandards.com rowder VLSI Standards, Inc. Order Curritry San Jace State Person Marc Helvey, ed. 108 Country			
	lateral distance			
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Calibration of	AEM		Characterized by	
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	VVLIW			
Calibration of				
	Web address http			
Provider No		://www.visistanda	ards.com	
Provider	VLSI Standards, Inc.			
Contact Person	Marc Helvey, ext. 108	Country	USA	
Email	sales.support@vlsistd.com	City	San Jose	
Phone	(408) 428-1800	City Code	CA 95134-2006	
	r	Street + No	3087 North First Street	